# Cohesive Techniques for Cell Layout Optimization Supporting 2D Metal-1 Routing Completion

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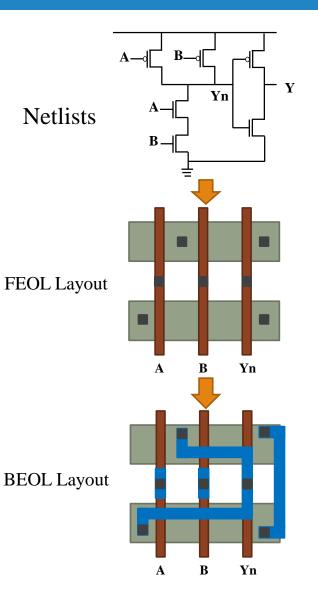
### **Motivation**

#### • Till today: Standard cell layout is done manually in industry

- Cell topology generation & internal net routing are not tightly coupled
   Produce inferior layouts wrt. cell size and routing completion
- Now: Increase the demand for fast and automatic exploration & generation of standard cell layouts
  - Need a quick evaluation vehicle of DTCO(design-technology cooptimization)
  - Need quick and quality competitive layout generation
    - Multiple sets of library to cope with broad range of product groups
    - Libraries for derivative processes

### **Cell Layout Generation**

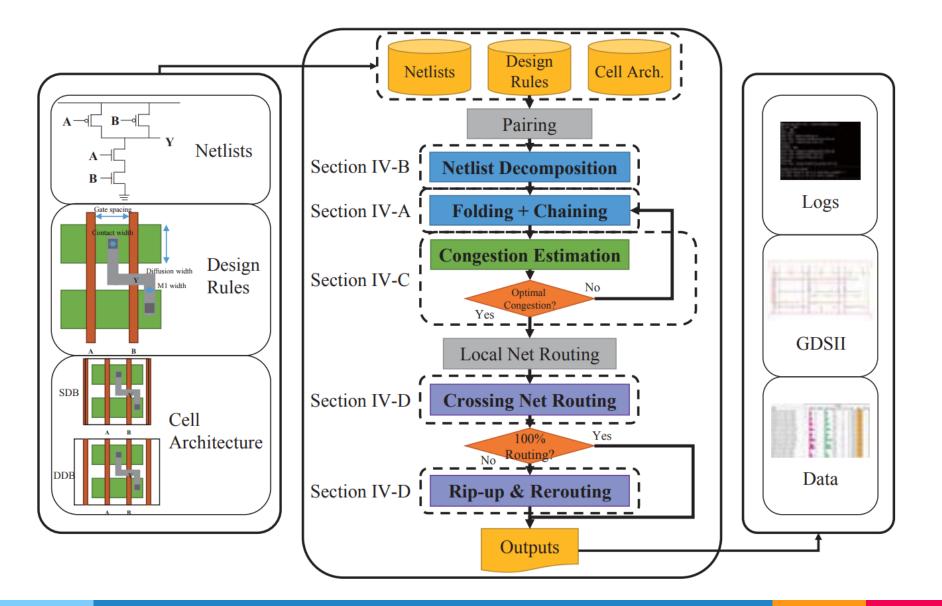
- Cell topology generation (Front End Of Line layout)
  - Determine gate poly order
  - Minimize area
     & enable 100% of internal routing
- Internal routing (Back End Of Line layout)
  - Assume 2D metal-1 routing
  - Route internal nets
  - Minimizing M2 usage



### **Related Works**

- Design Rule Evaluator <sup>[1]</sup>
  - Evaluate design rules and cell layout simultaneously
  - BEOL layout is not generated
- Standard cell routing via SAT <sup>[4]</sup>
  - Find legal routing among candidate routes by SAT
  - No consideration of FEOL to enhance routability
  - Run time and memory explosion
- BonnCell: Automatic layout of leaf cells <sup>[5]</sup>
  - Generate cell layouts through recursive enumeration
  - Internal net routing using mixed-integer programming
  - No consideration of correlation between FEOL & BEOL

### **Proposed Flow of Cell Layout Generation**



### **Cohesive Technologies for Cell Layout Optimization**

Newly devised following methodologies

**1. Chaining combined with folding** 

2. Netlist decomposition

3. Gate poly ordering combined with routing congestion estimation

4. 2D routing with minimal resource

### Folding

 Splitting a transistor with large width into multiple smaller ones in parallel connection

### Chaining

 Abutting transistor pairs by sharing the same active area

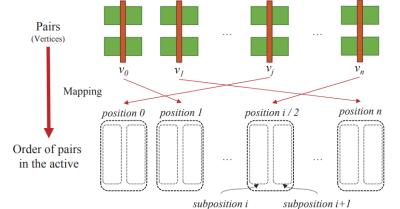
- **Problem formulation** 
  - Given: transistor pairs including folded ones
  - Objective: abut the pairs as a chain



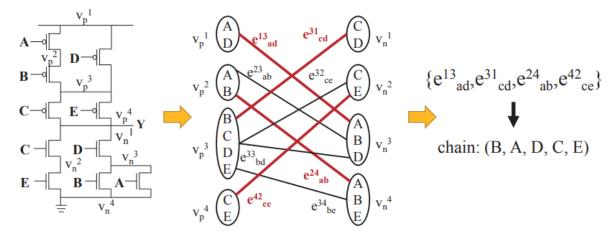
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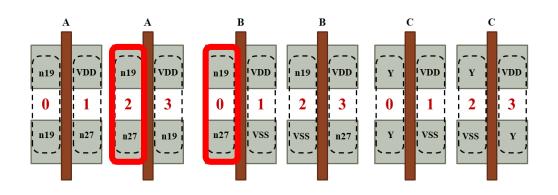
- Previous method <sup>[6]</sup>
  - Fold all transistors larger than maximum width
  - Netlist  $\rightarrow$  Bipartite graph  $\rightarrow$  Transistor chain

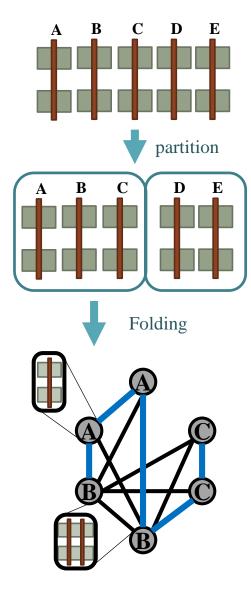


- Significant runtime sacrifices
  - Edges of bipartite graph increase significantly when transistors are folded
     → excessive exploration of redundant folded transistors
  - ≥12 hours for cells having more than 20 folds

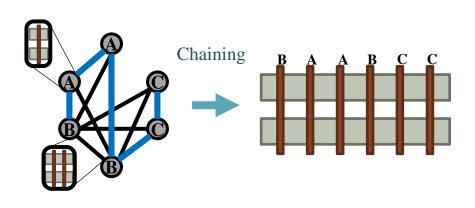
#### Proposed method

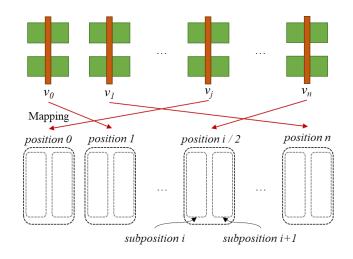
- 1. Partition transistor pairs to be abutted into a single chain
  - Use previous Bipartite graph method<sup>[6]</sup>
  - Consider transistor pairs as unfolded
- 2. Derive transistor abutment graph
  - Vertex: transistor pair including folded one
  - Edge: possibility of abutment between tr. Pairs
  - Type: source/drain combination of a pair





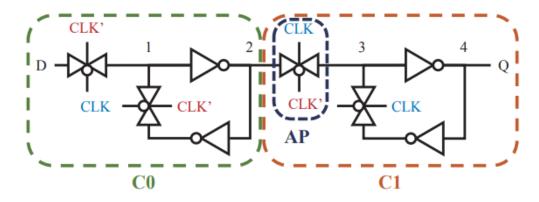
- 3. Formulate as Hamiltonian path problem
  - Hamiltonian path represents <u>a chain with abutted transistors</u>
- 4. Solve the problem with SAT formulation
  - Integration of gate poly ordering and abutment constraints
  - SAT solver reduce run time
  - Generate multiple gate poly ordering candidates
     → higher possibility of internal routing completion





### 2. Netlist Decomposition

• Combine theoretical knowledge and designer's experience



• Partition a netlist if multiple data flow feedback loops exist

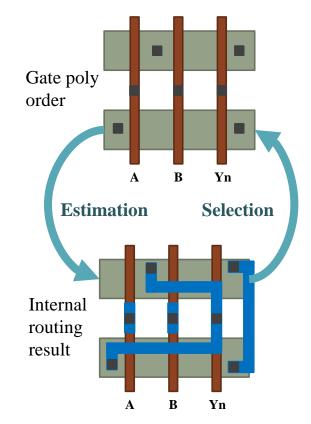
#### Results

- Trade-off between area optimization and internal routing completion
- Proof of effectiveness by experiments

   *→* increased routing completion for sequential logic cells (flip-flops)

### 3. Gate Poly Ordering Combined with Routing Congestion Estimation

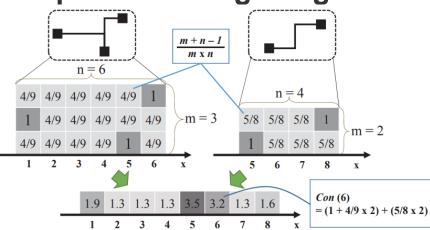
- Correlation of gate poly order and internal routing result
  - Not fully considered in previous related works
- Ordering gate polys to have higher possibility of routing completion
- Estimate routing congestion for every instance of FEOL layout

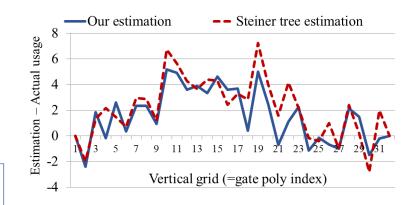


• Find ordering instances with less routing congestion

### 3. Gate Poly Ordering Combined with Routing Congestion Estimation

Proposed routing congestion estimation



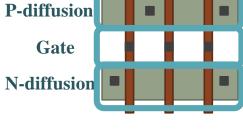


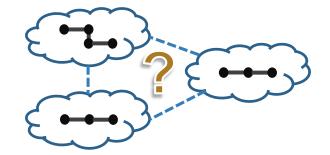
- Estimation for each net
  - Bounding box of all pins
  - Possibility of grid occupation
    - Contact: 1
    - Otherwise: (Half-perimeter / # of bins)
- More precise estimation compared to STST (Single Trunk Steiner Tree) method
  - Actual vertical track usage vs. estimated usage

## 4. 2D Routing with Minimal Resource

- Routing Strategy
  - Local nets
    - Connection of contacts belongs to a single region
  - Crossing nets
    - Connection of contacts in between multiple regions
  - Local nets → Crossing nets

- Issues on crossing net routings
  - Planarity
    - Possibility of routing to be done in a single plane
  - Sequentiality
    - Effect of routing order on routing completion





## 4. 2D Routing with Minimal Resource

#### Rubber Band Equivalent (RBE)

 Shortest path connecting two points, detouring blockages

### Critical Cut

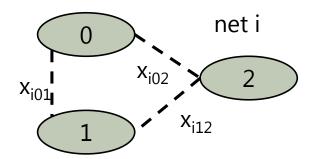
A shortest line between two blockages' corner or tip

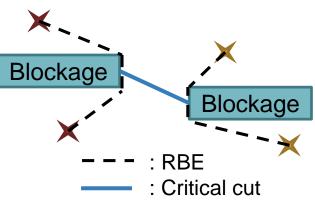
### Planarity Check

• All critical cuts  $\rightarrow$  flow  $\leq$  capacity

#### Solved with an ILP

- Minimized routing length with
  - Sub nets should be connected
  - Planarity must be satisfied





#### • PDK & Spice netlist

- 45nm FreePDK & NanGate standard cell library
- 28nm Industry partner's PDK & cell library
- Net specification of 28nm cell library

	#Cells	#Nets	#Nets per cell
Comb. logic	48	354	4-12
Flip-flops	8	151	14-24
Total	56	505	4-24

#### Results

- Cell generation
  - **100%** routing completion with 9 & 11 tracks
- Run time:
  - About **1 hour** for 28nm library (56 representative cells)
  - $\leq$  3 hours for NanGate cell library (all cells)

#### Effectiveness of our techniques

- Netlist decomposition
  - → Routing completion increase(M1: 22%p, total: 17%p) with run time reduction
- Chaining combined with folding
   → 83% run time reduction, with 7%p total routing completion increase
- New congestion estimation method
   → Ensure 100% routing completion
- Cross routing with planarity
   → Ensure 100% routing completion

			Routing		
	Techniques	Netlist	completion		Run time (sec.)
			M1	M1+M2	TG / Rout' / Total
		Combs.	96%	100%	930 / 50 / 980
	All-applied	FFs	70%	100%	683 / 267 / 950
		Total	89%	100%	1613 / 317 / 1930
	Netlist	Combs.	-	-	-/-/-
	Decomp. (x)	FFs	48%	83%	1124 / 163 / 1287
	Chaining + Folding (x)	Combs.	85%	89%	10394 / 36 / 10430
		FFs	70%	100%	687 / 261 / 948
		Total	81%	93%	11081 / 297 / 11378
	New Congestion	Combs.	97%	100%	933 / 111 / 1044
	Estimation (x)	FFs	61%	91%	687 / 261 / 948
		Total	86%	97%	1522 / 266 / 1788
	Planar Cross Routing (x)	Combs.	95%	99%	932 / 47 / 979
		FFs	70%	100%	683 / 260 / 943
	Kouning (X)	Total	88%	99%	1615 / 307 / 1922

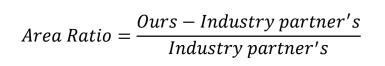
#### Evaluation of layout quality

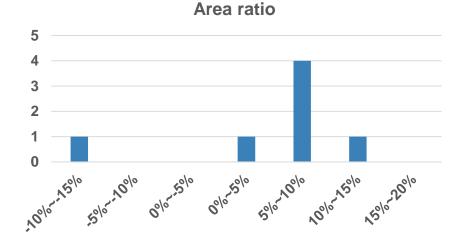
Comparison with industry partner's library developed manually

#### Layout area

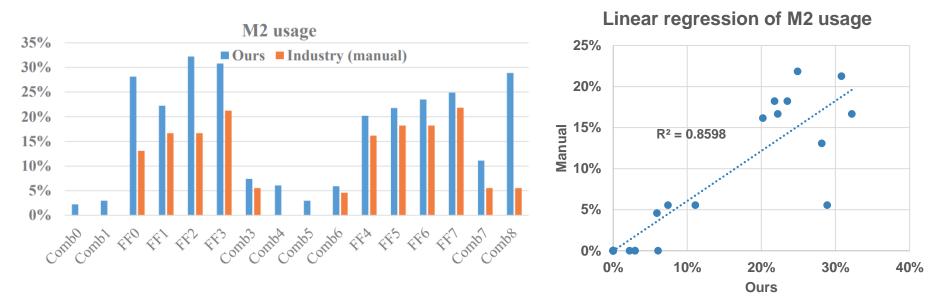
- Flip-flop area is larger than that of manual by 5~10%
- In digital block, comb. Cell (60%) + flip-flops (40%)
   → Area overhead in digital block = 2~4%

Cell type	Cell count	Area ratio
Comb. logic	48	0%
Flip-flops	8	5~10%





• M2 Usage



- Occupy 7%p more M2 resource on average
- Quickly generated (several days vs. within an hour)
- Positive correlation with manual

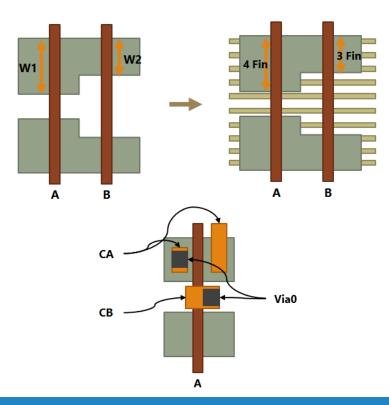
### **Conclusions & Ongoing works**

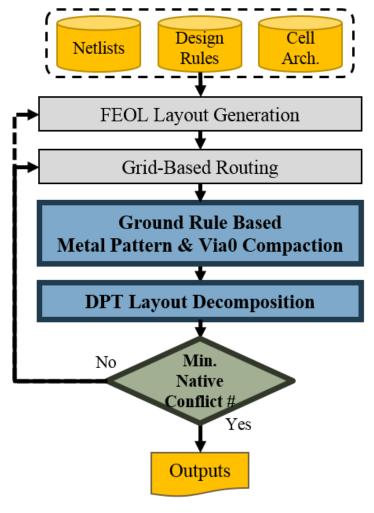
- Full automation for generating cell layouts
  - Cohesive techniques are effective to improve quality of the cell generator
  - Comparable to the industry partner's manual layouts with a extremely short time
  - Can be used as a cornerstone for migrating from planar technology to 3D FinFET technology
  - Can be used valuably as core engine in DTCO

Ongoing works

## **Ongoing works**

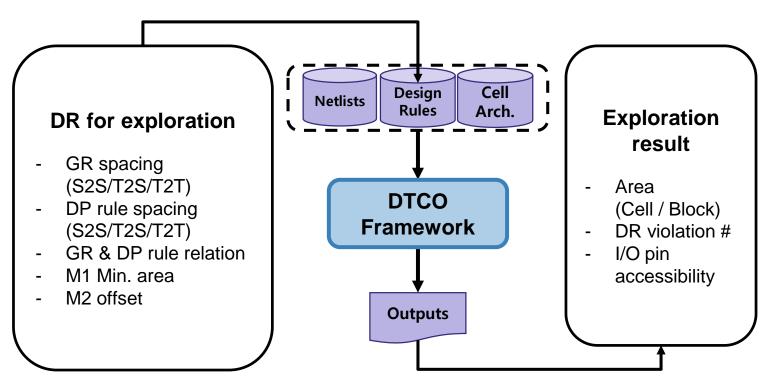
- Adaptation for FinFET technology
  - Discrete Fin number & MEOL
  - Increased design rule complexity
  - DPT (Double patterning) is needed





## **Ongoing works**

• DTCO (Design Technology Co-Optimization) Framework



- Can be used as exploration tool of design rule and cell architecture
- Enable co-optimization of design & process technology



# Thank you!



## **Q & A**